Hybrid 8j374 Traveler

May 26, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J374 has die: 169-044 169-045 169-050 169-018 170-076 170-082 170-083 170-085

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

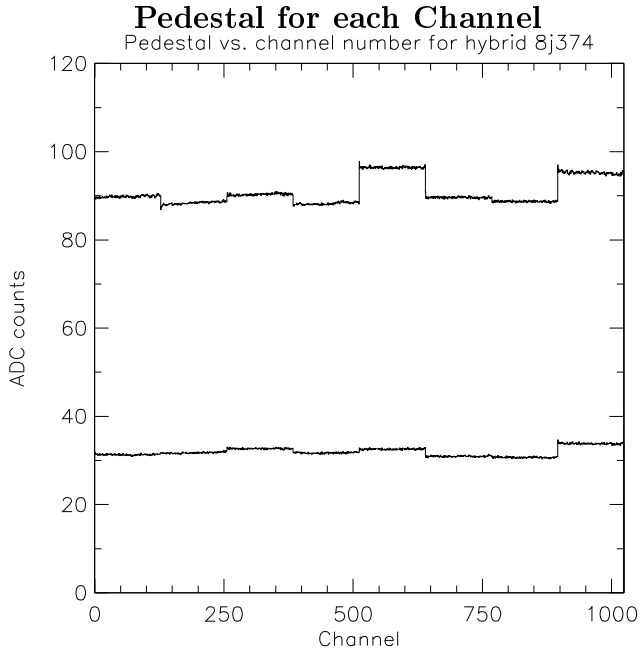
```
% Hybrid 8j374 classification info. Created 11:00:23 05/24/00

Hybrid 8j374 quality: fair
Chip classification: good fair fair good fair good good good
Bad channels: none
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-22-106 1-22-107 1-23-107
   1-26-106 1-26-107 1-26-66 1-27-107 1-29-106 1-29-107 1-29-95 1-31-106
   1-31-107 1-31-2 1-33-106 1-33-107 1-42-106 1-42-107 1-43-107 1-9-107
   2-30-94 4-42-112
Channels at pedestal needed for DCMS: 31.7 32.6 32.7 30.7 33.5 34.6 32.6 33.6
```

4 Comments

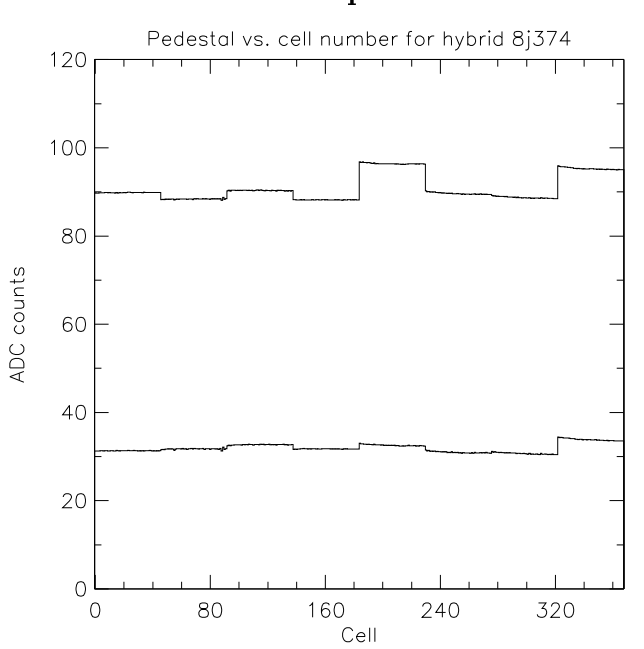
HV tested.

5 Pedestal

The following plot shows the pedestals vs. channel number with and without charge injection:



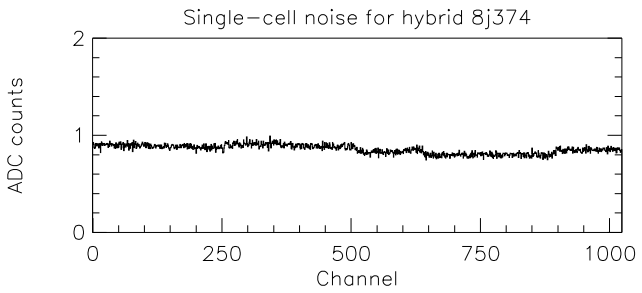
The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

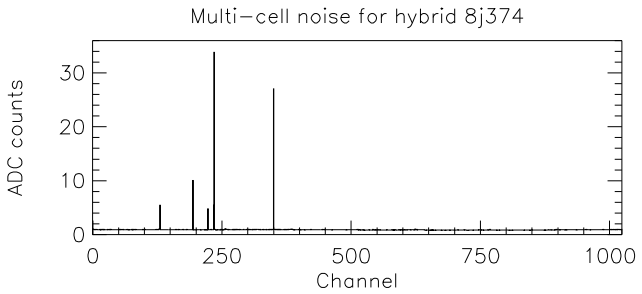


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

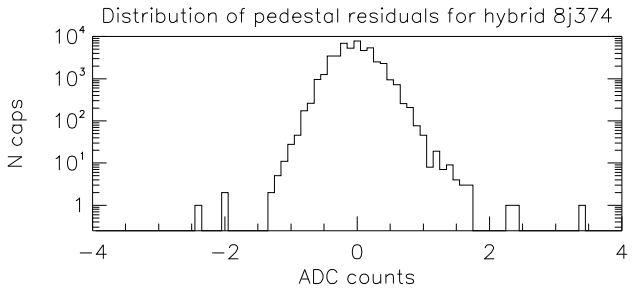
RMS Noise

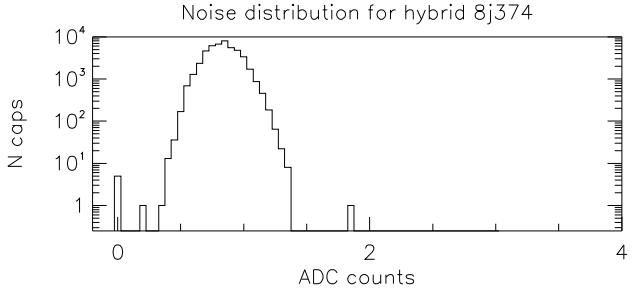




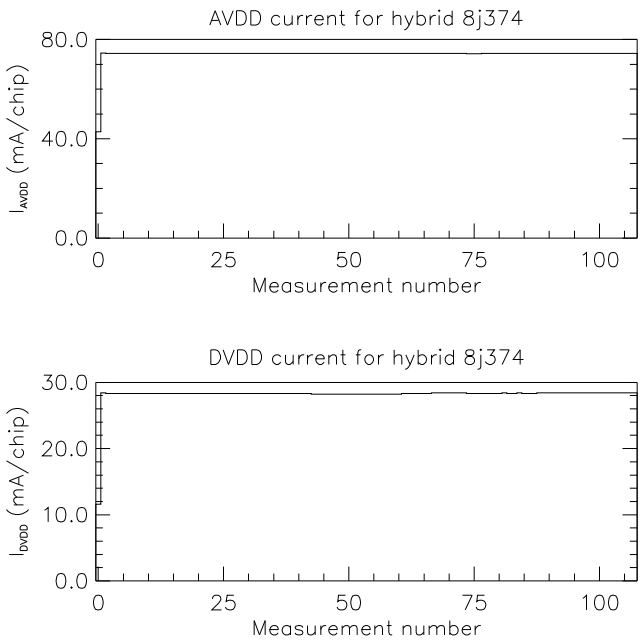
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in